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(12) **United States Design Patent**
Yasuda et al.

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(45) **Date of Patent:** **** Mar. 22, 2011**

(54) **ELASTIC MEMBRANE FOR SEMICONDUCTOR WAFER POLISHING APPARATUS**

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(**) Term: **14 Years**

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(30) **Foreign Application Priority Data**

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Aug. 27, 2009 (JP) 2009-19721

(51) **LOC (9) Cl.** **13-03**

(52) **U.S. Cl.** **D13/182**

(58) **Field of Classification Search** D13/182;
257/E21.304; 451/66, 288, 289
See application file for complete search history.

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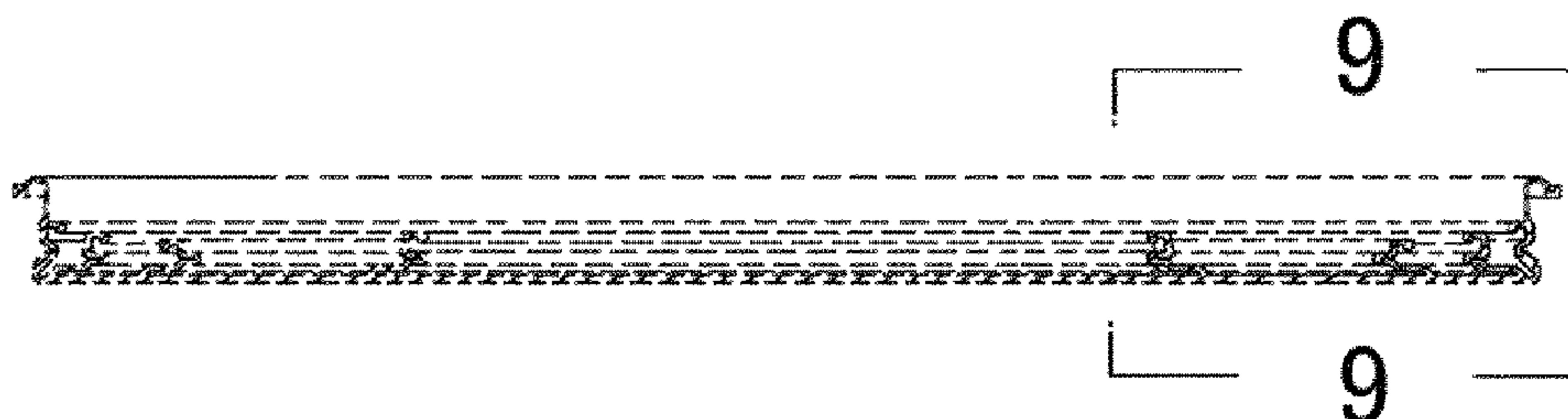
(57) **CLAIM**

The ornamental design for an elastic membrane for semiconductor wafer polishing apparatus, as shown and described.

DESCRIPTION

FIG. 1 is a bottom view of an elastic membrane for semiconductor wafer polishing apparatus showing our new design; FIG. 2 is a top view thereof; FIG. 3 is a front view thereof; FIG. 4 is a right side view thereof; FIG. 5 is a rear view thereof; FIG. 6 is a left side view thereof; FIG. 7 is a perspective view, observed from above thereof enlarged for ease of illustrations; FIG. 8 is a cross-section view taken along the line 8—8 of FIG. 2 thereof; FIG. 9 is an enlarged view of part 9 of FIG. 8 thereof; FIG. 10 is a bottom view thereof; FIG. 11 is a top view thereof; FIG. 12 is a front view thereof; FIG. 13 is a right side view thereof; FIG. 14 is a rear view thereof; FIG. 15 is a left side view thereof; FIG. 16 is a perspective view, observed from above thereof enlarged for ease of illustrations; FIG. 17 is a cross-section view taken along the line 17—17 of FIG. 11 thereof; FIG. 18 is an enlarged view of part 18 of FIG. 17 thereof; FIG. 19 is a bottom view thereof; FIG. 20 is a top view thereof; FIG. 21 is a front view thereof; (rear view is omitted since it is identical with the front) FIG. 22 is a right side view thereof; (left side view is omitted since it is identical with the right side view) FIG. 23 is a perspective view, observed from above thereof enlarged for ease of illustrations; FIG. 24 is a cross-section view taken along the line 24—24 of FIG. 20 thereof; and, FIG. 25 is an enlarged view of part 25 of FIG. 24 thereof. The broken lines depict environmental subject matter only and form no part of the claimed design.

1 Claim, 9 Drawing Sheets



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FIG.1

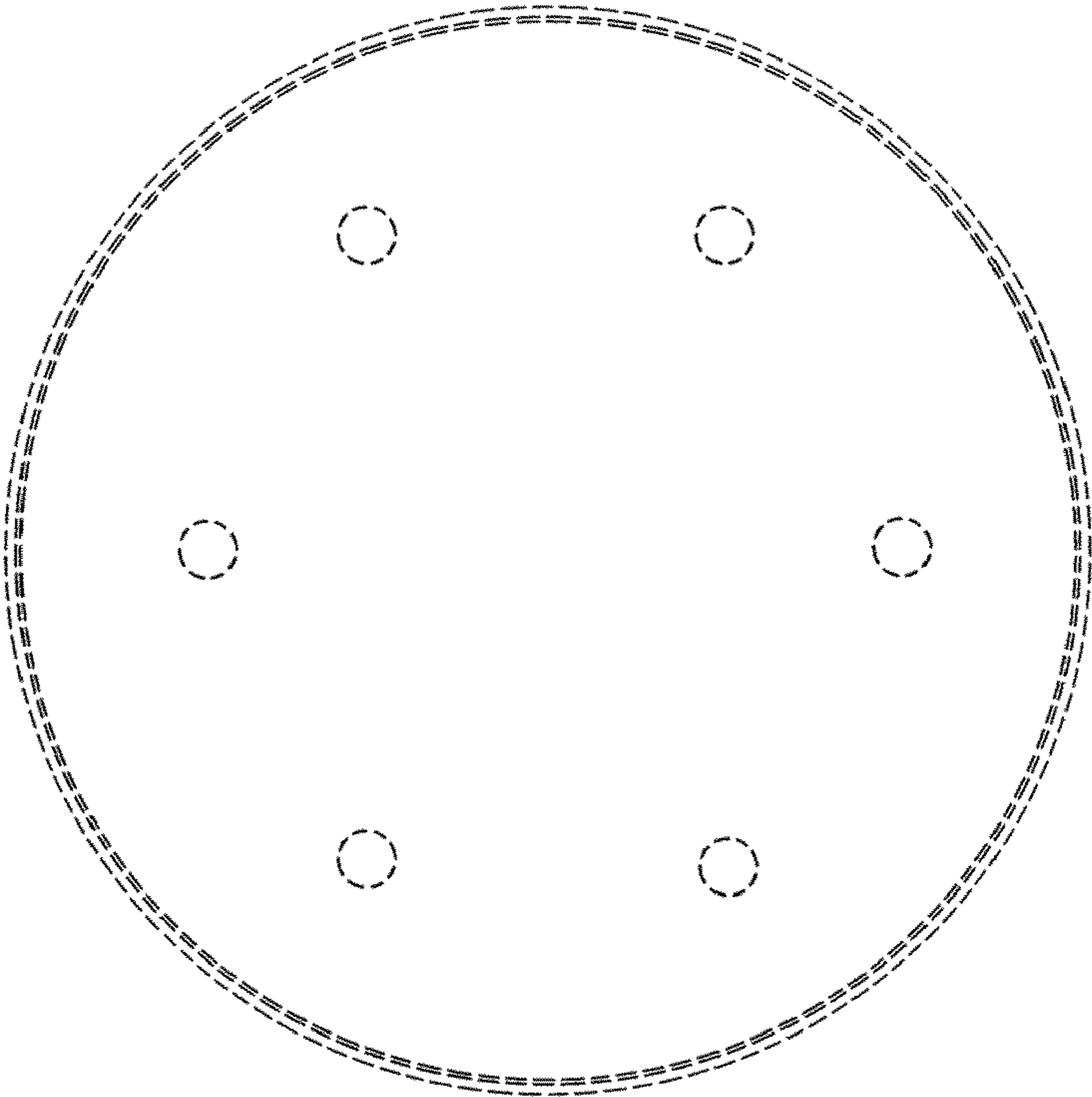


FIG.2

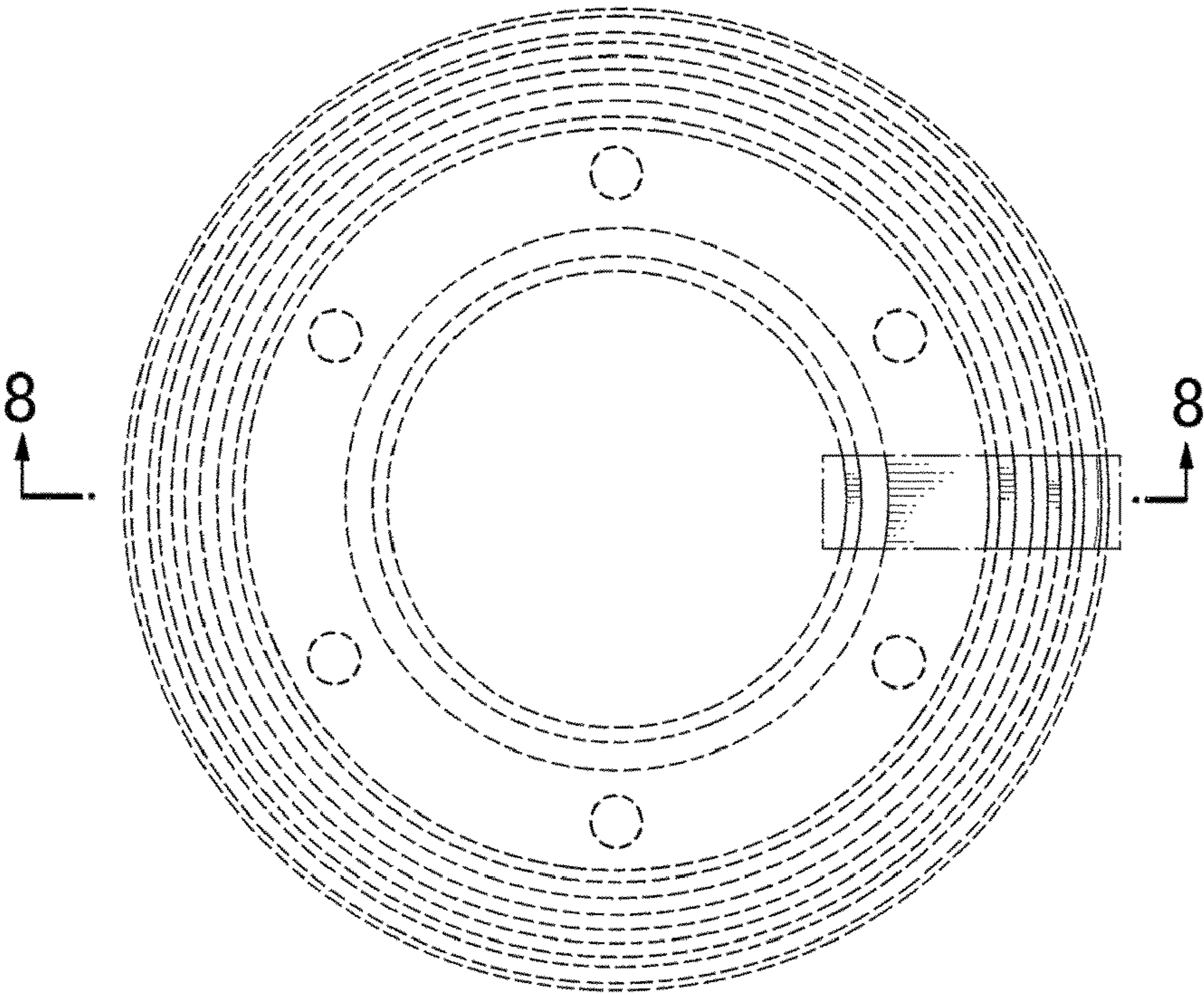


FIG.3



FIG.4

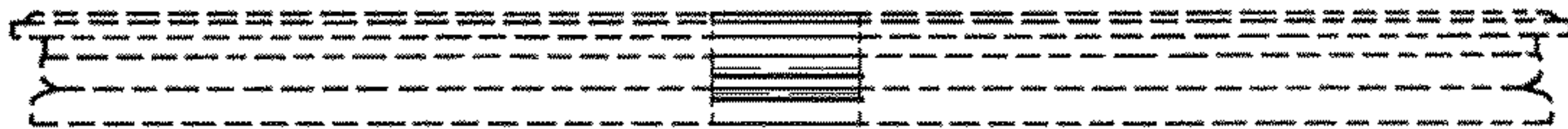


FIG.5

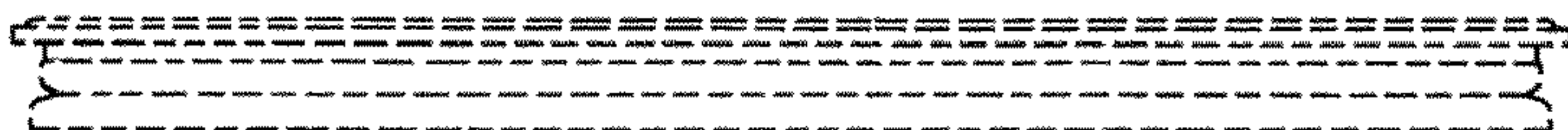


FIG.6



FIG.7

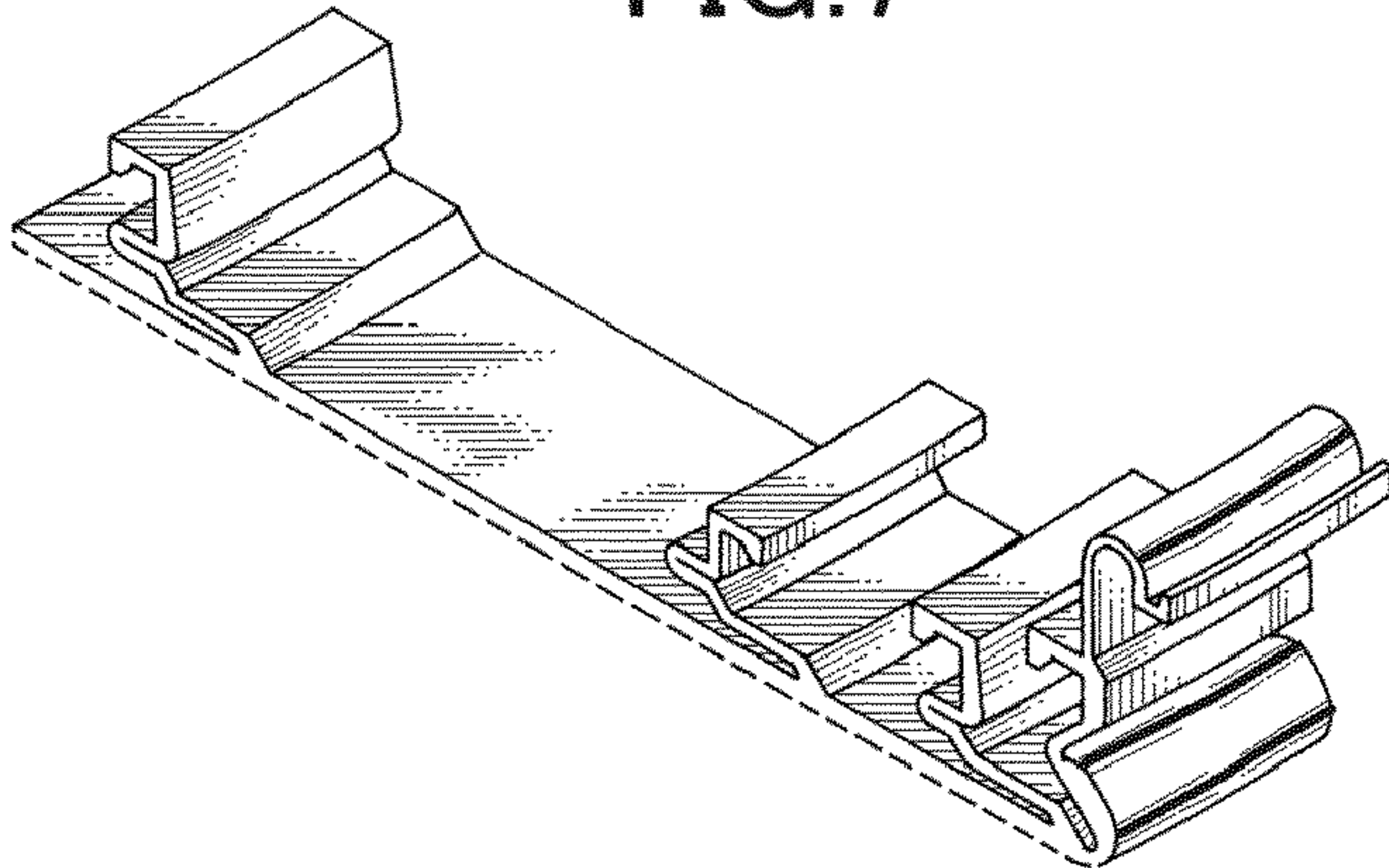


FIG.8

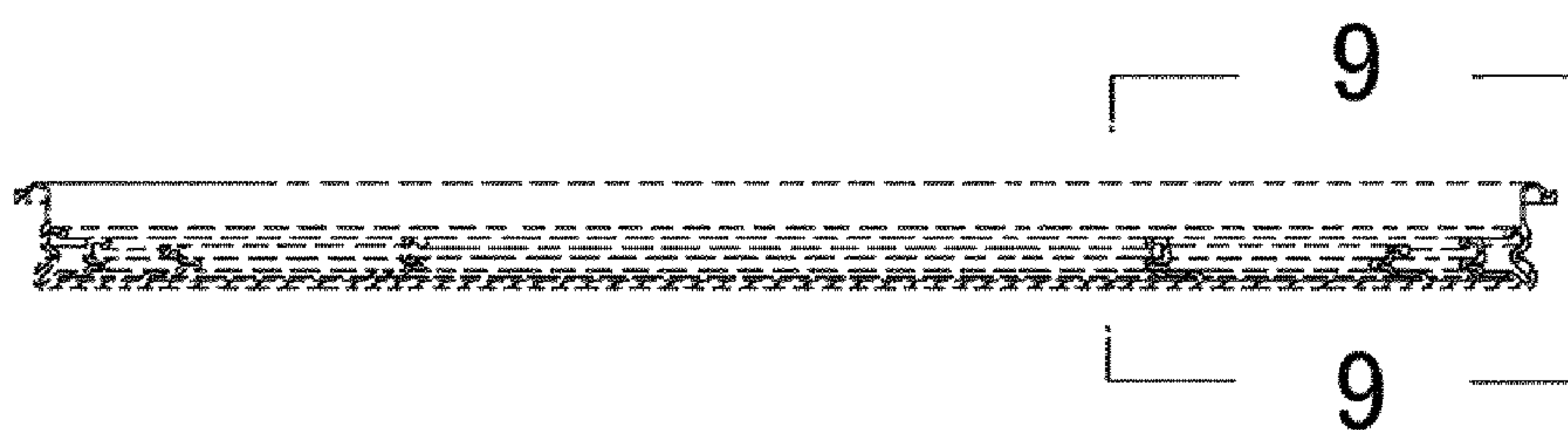


FIG.9

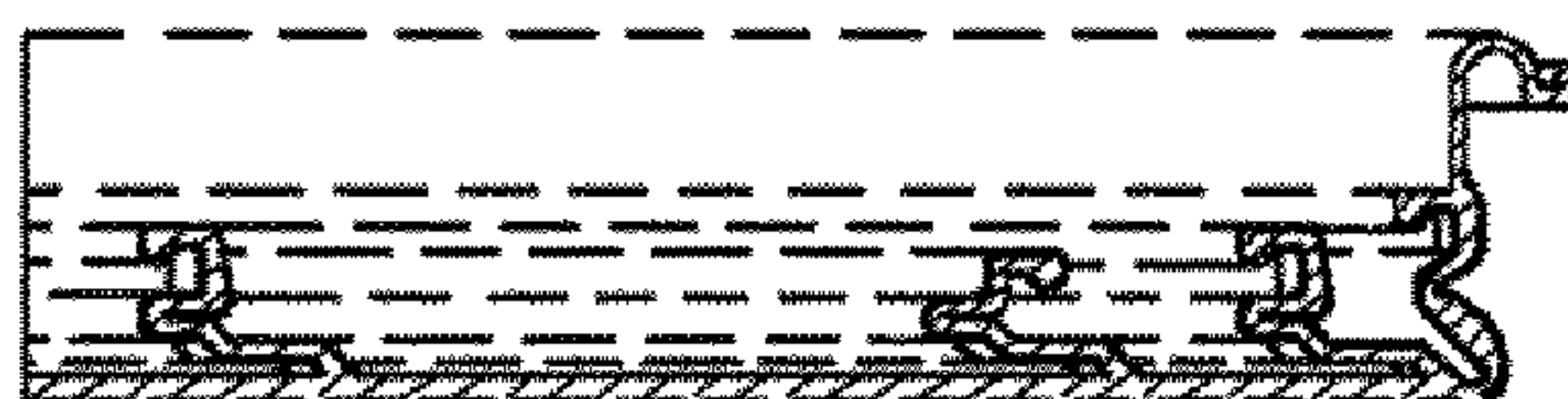


FIG.10

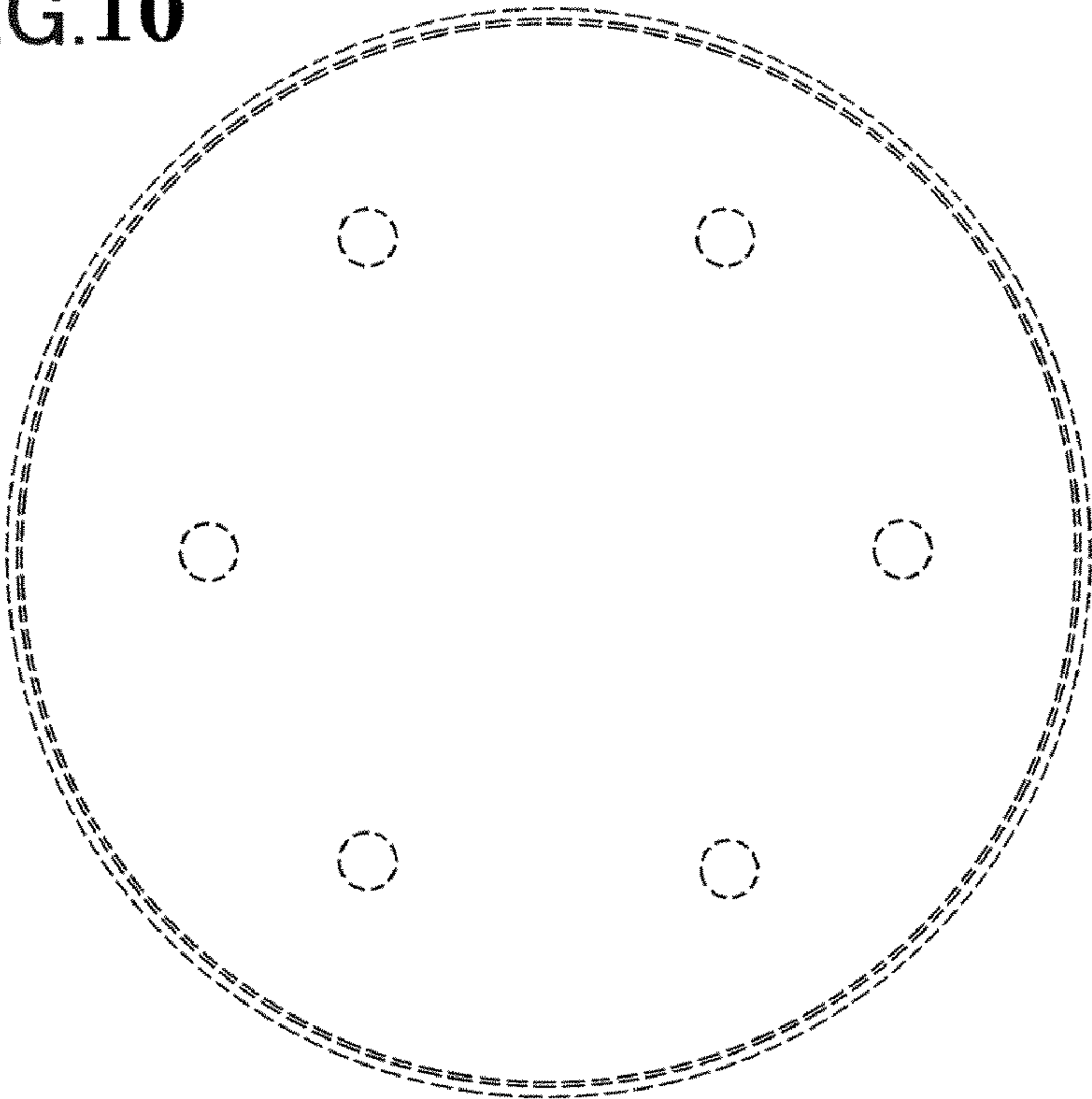


FIG.11

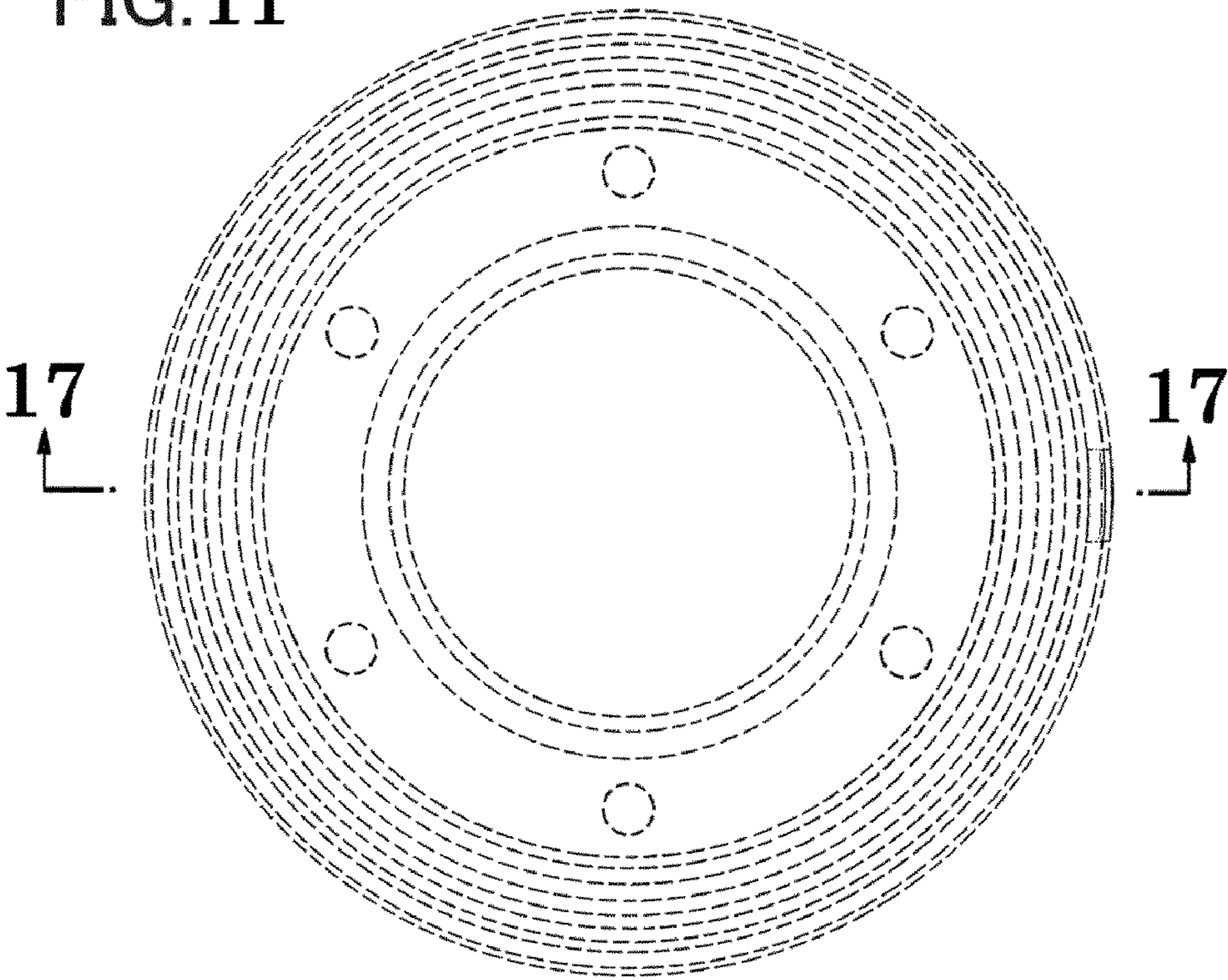


FIG.12



FIG.13

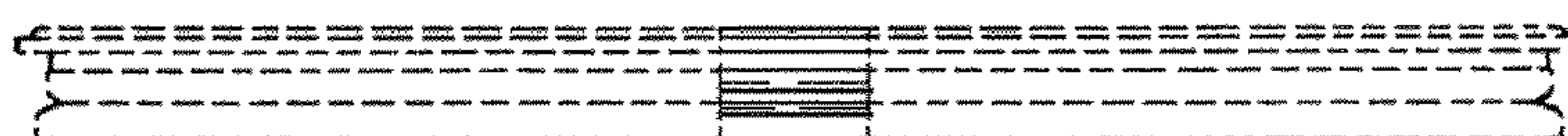


FIG.14

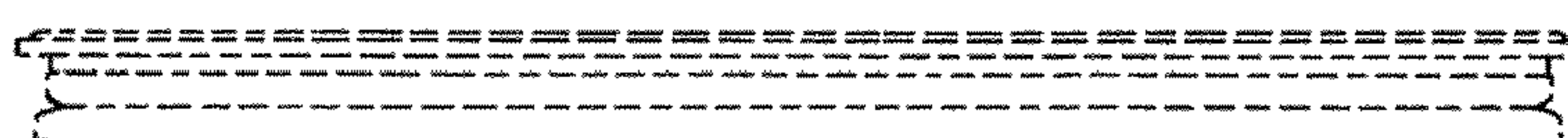


FIG.15

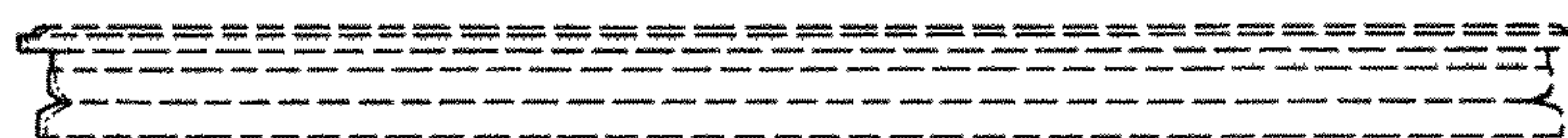


FIG.16

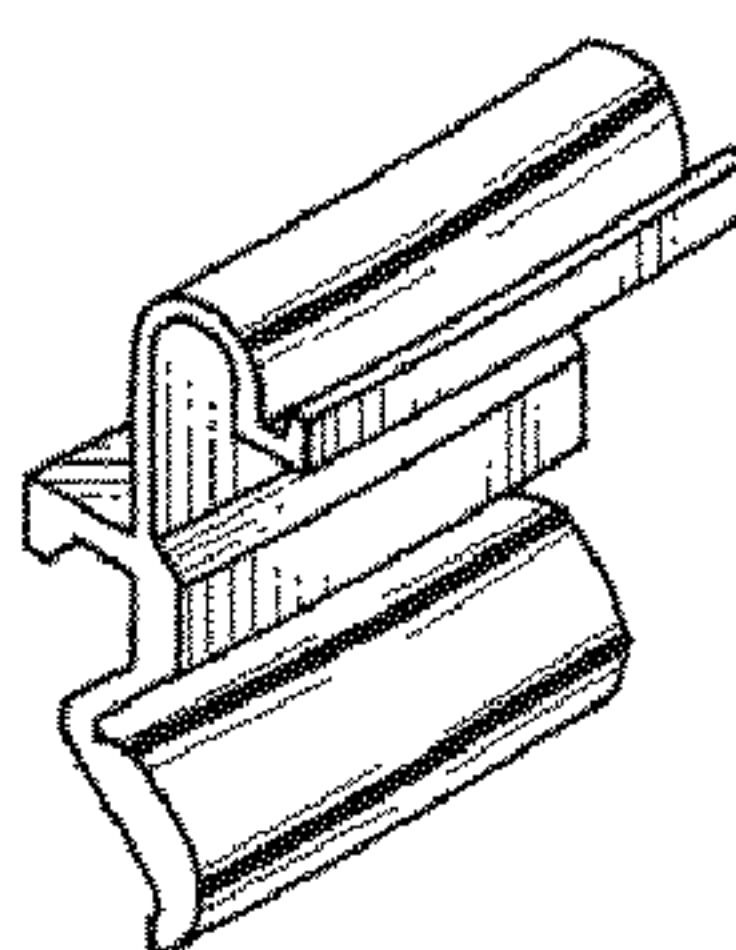


FIG.17

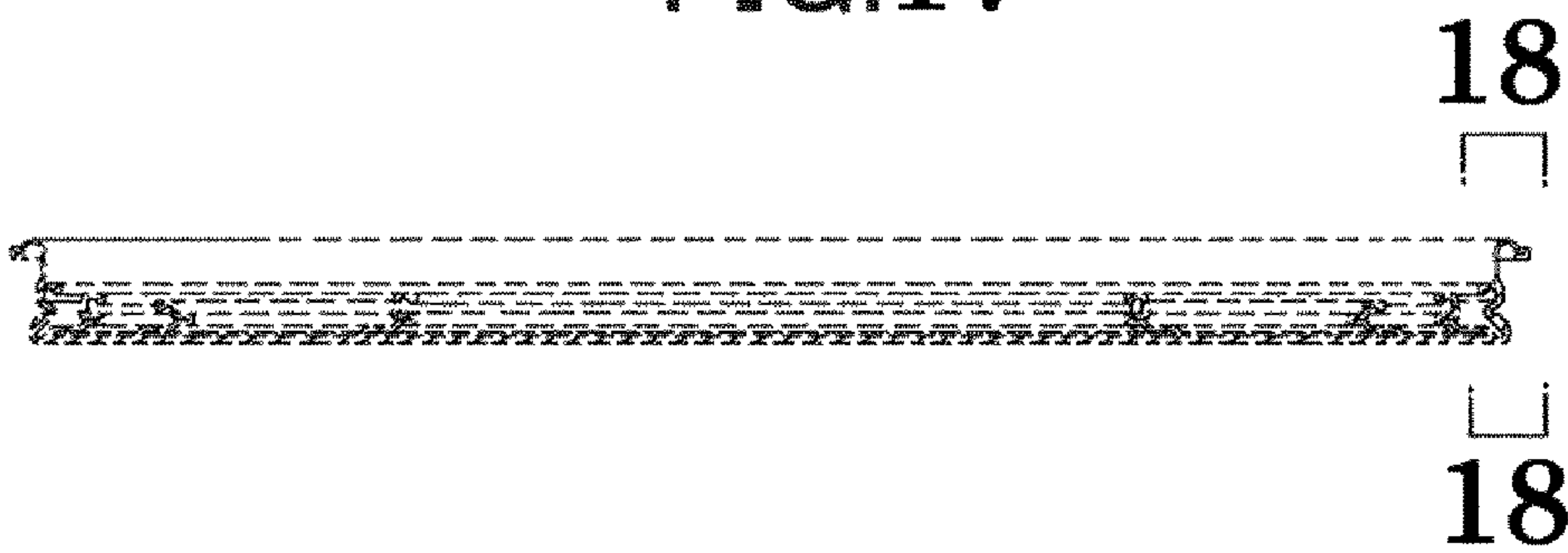


FIG.18

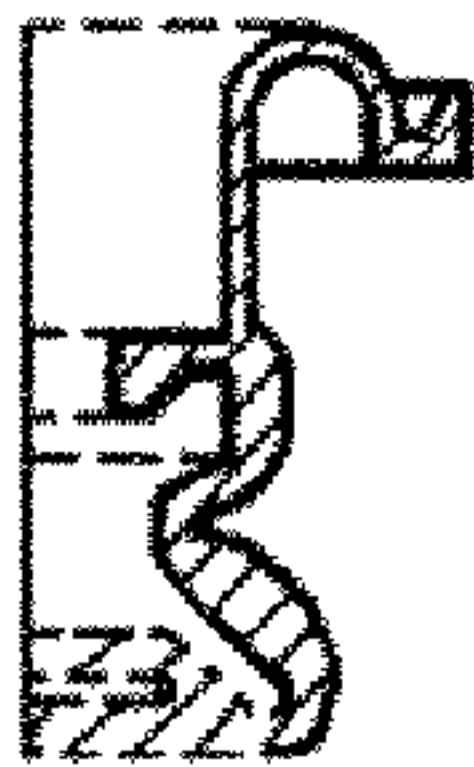


FIG.19

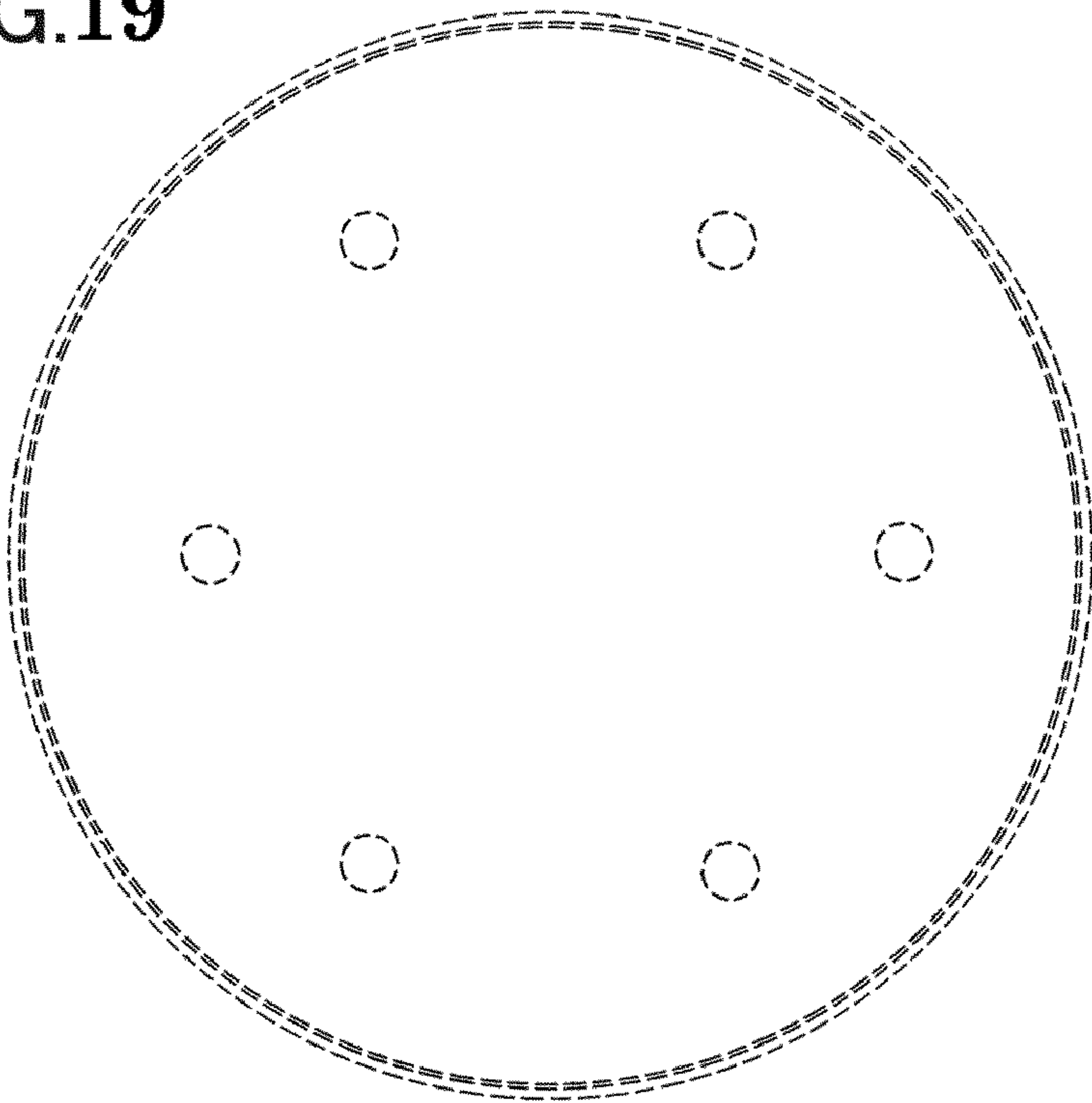


FIG.20

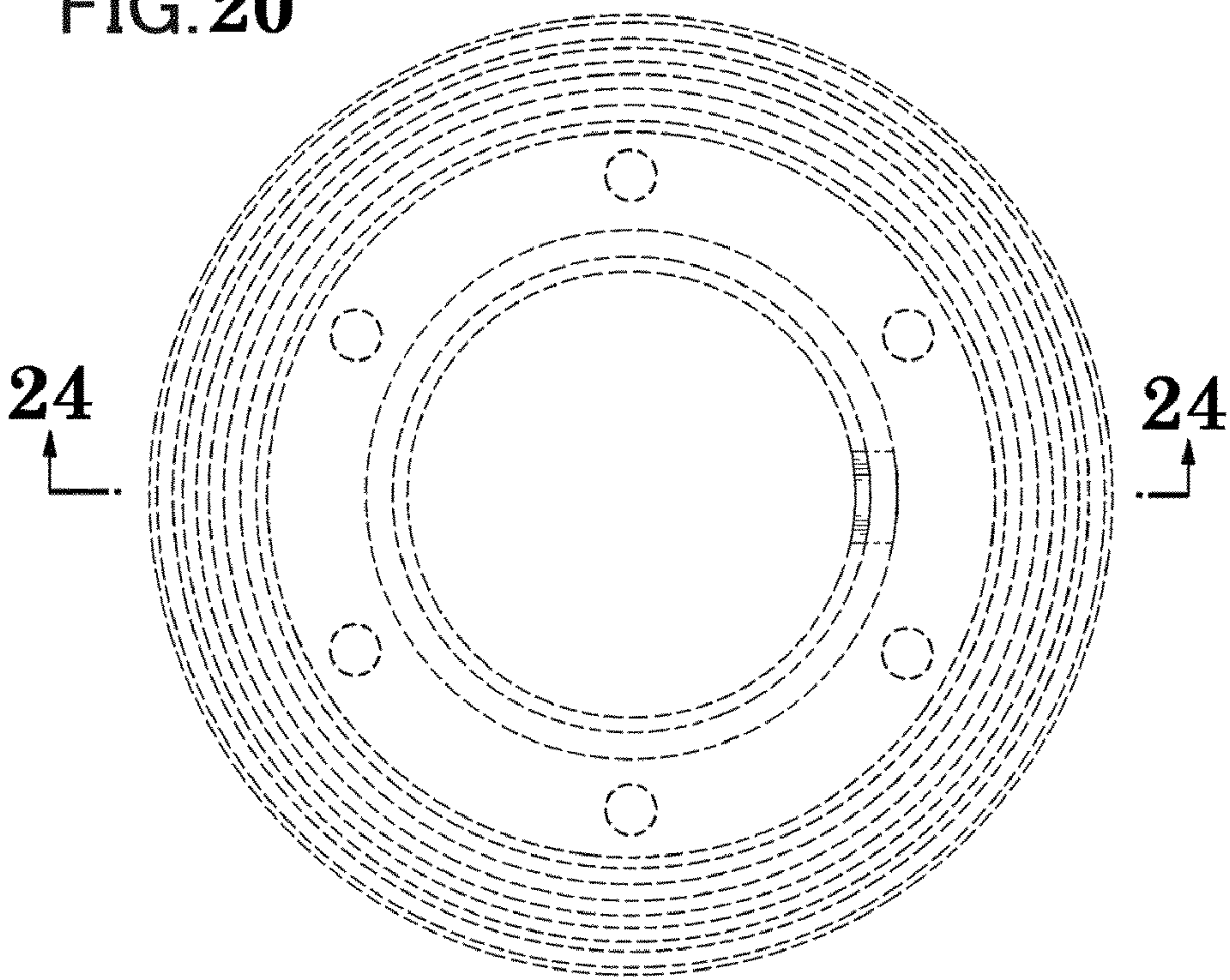


FIG. 21



FIG. 22



FIG. 23

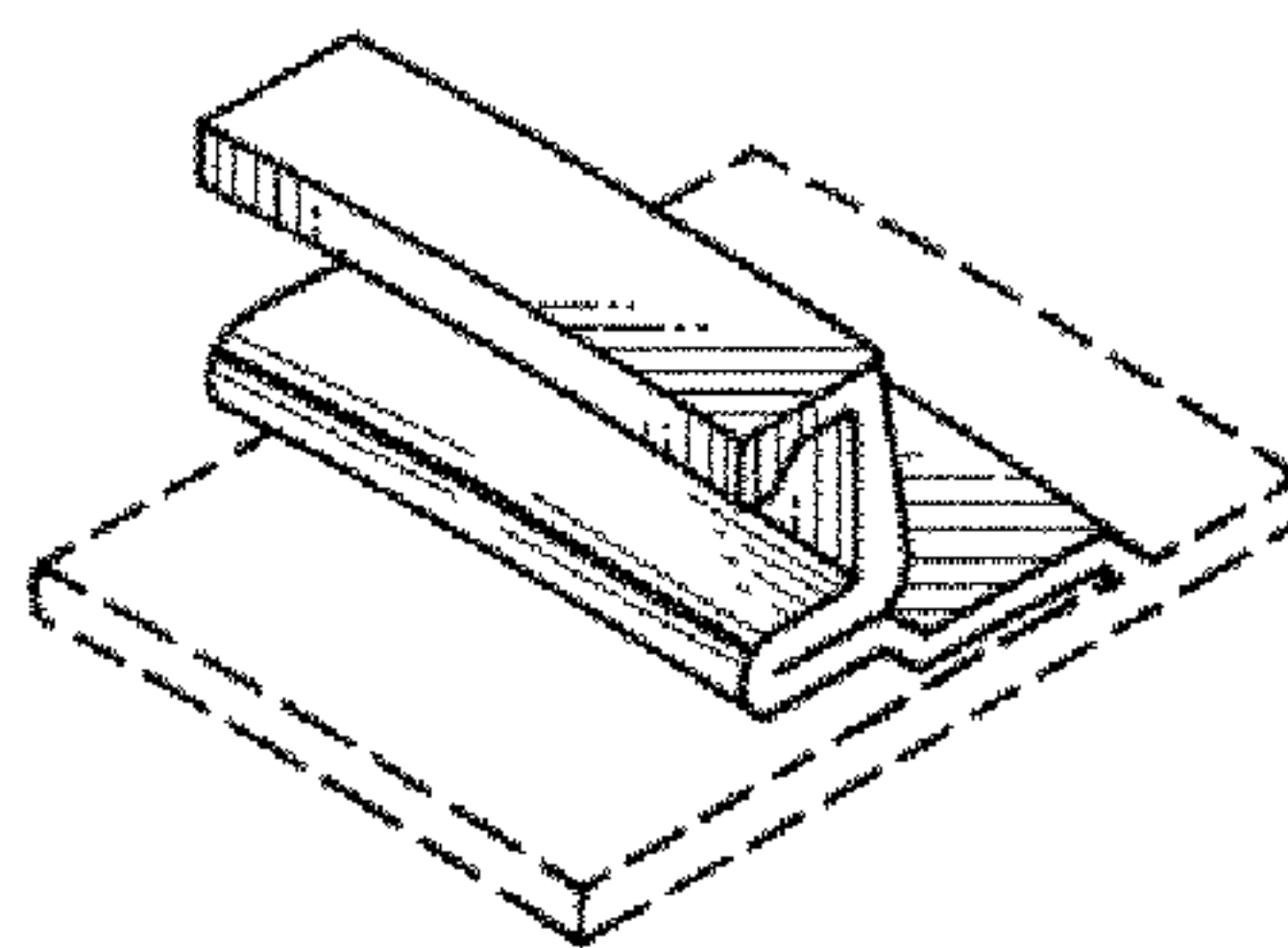


FIG. 24

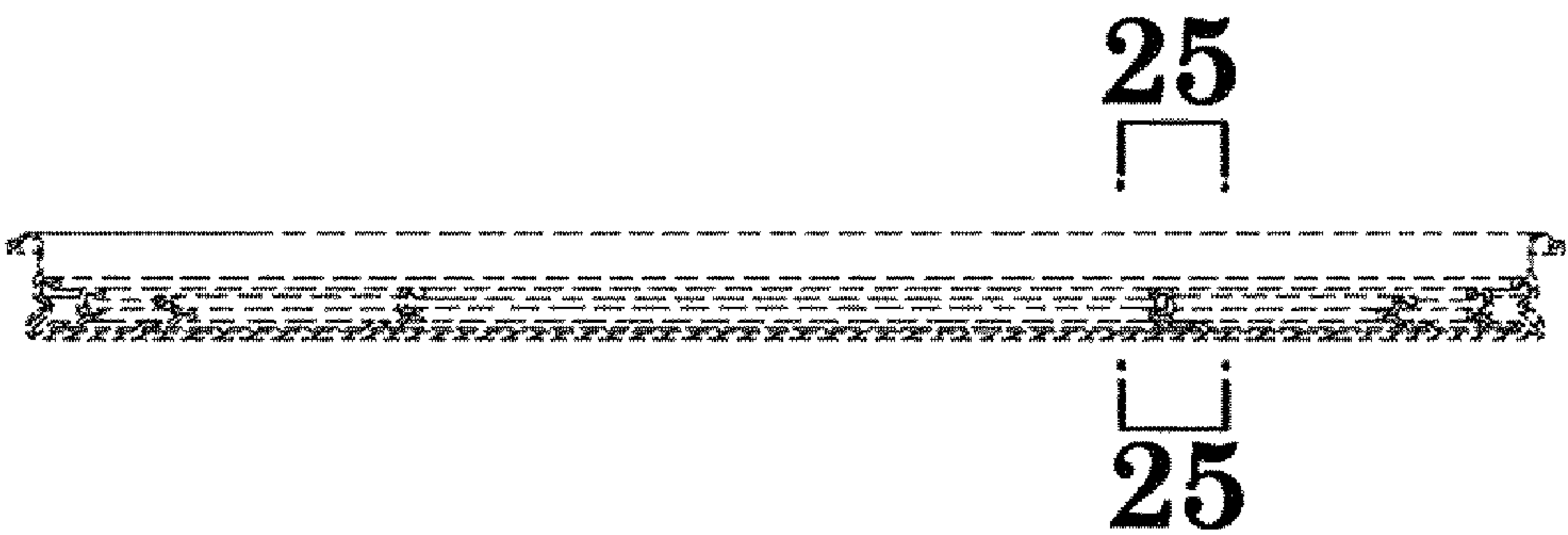


FIG. 25

